TOSHIBA Field-Effect Transistor Silicon N-Channel MOS Type

# SSM3K35MFV

- High-Speed Switching Applications
- Analog Switch Applications
- 1.2 V drive

• Low ON-resistance :  $R_{on}$  = 20  $\Omega$  (max) (@V<sub>GS</sub> = 1.2 V)

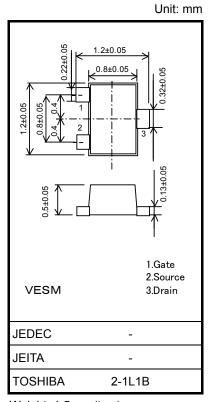
:  $R_{on}$  = 8  $\Omega$  (max) (@V<sub>GS</sub> = 1.5 V) :  $R_{on}$  = 4  $\Omega$  (max) (@V<sub>GS</sub> = 2.5 V) :  $R_{on}$  = 3  $\Omega$  (max) (@V<sub>GS</sub> = 4.0 V)

# Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit		
Drain-source voltage		$V_{DSS}$	20	V	
Gate-source voltage		$V_{GSS}$	±10	V	
Drain current	DC	ΙD	180	mA	
	Pulse	IDP	360		
Drain power dissipation		P <sub>D</sub> (Note 1)	150	mW	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature		T <sub>stg</sub>	-55~150	°C	

Note 1: Mounted on an FR4 board

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu Pad: } 0.585 \text{ mm}^2)$ 



Weight: 1.5 mg (typ.)

#### **Electrical Characteristics (Ta = 25°C)**

Charac	cteristic	Symbol	Test Condition		Min	Тур.	Max	Unit
Gate leakage curre	ent	I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$		_	_	±10	μА
Drain-source brea	kdown voltage	V (BR) DSS	$I_D = 0.1 \text{ mA}, V_{GS} = 0 \text{ V}$		20	_	_	V
Drain cutoff curren	t	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V		_	_	1	μА
Gate threshold vol	tage	V <sub>th</sub>	$V_{DS} = 3 \text{ V}, I_D = 1 \text{ mA}$		0.4	_	1.0	V
Forward transfer a	dmittance	Y <sub>fs</sub>	$V_{DS} = 3 \text{ V}, I_D = 50 \text{ mA}$	(Note 2)	115	_	_	mS
Drain-source ON-resistance		R <sub>DS</sub> (ON)	$I_D = 50$ mA, $V_{GS} = 4$ V	(Note 2)	_	1.5	3	Ω
			$I_D = 50 \text{ mA}, V_{GS} = 2.5 \text{ V}$	(Note 2)	_	2	4	
			$I_D = 5 \text{ mA}, V_{GS} = 1.5 \text{ V}$	(Note 2)	_	3	8	
			I <sub>D</sub> = 5 mA, V <sub>GS</sub> = 1.2 V	(Note 2)	_	5	20	
		C <sub>iss</sub>	V <sub>DS</sub> = 3 V, V <sub>GS</sub> = 0 V, f = 1 MHz		_	9.5		pF
		C <sub>rss</sub>			_	4.1		
		Coss			9.5			
Switching time	Turn-on time	t <sub>on</sub>	$V_{DD} = 3 \text{ V}, I_{D} = 50 \text{ mA},$ $V_{GS} = 0 \text{ to } 2.5 \text{ V}$		_	115	_	
	Turn-off time	t <sub>off</sub>			_	300	_	ns
Drain-source forward voltage		V <sub>DSF</sub>	$I_D = -180 \text{ mA}, V_{GS} = 0 \text{ V}$	(Note 2)	_	-0.9	-1.2	V

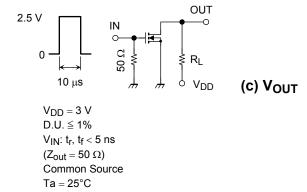
Note 2: Pulse test

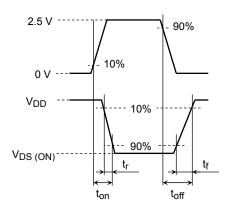
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## **Switching Time Test Circuit**

#### (a) Test Circuit

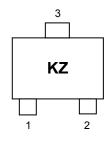


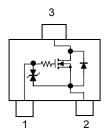




#### Marking

### **Equivalent Circuit (top view)**





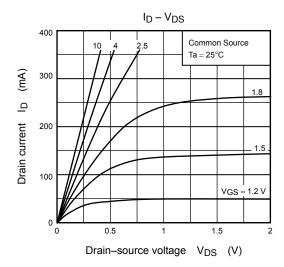
# **Notice on Usage**

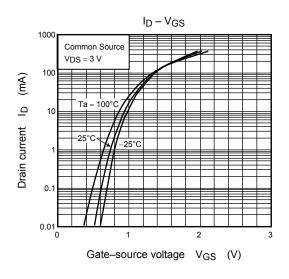
 $V_{th}$  can be expressed as the voltage between gate and source when the low operating current value is  $I_D$  = 1 mA for this product. For normal switching operation,  $V_{GS}$  (on) requires a higher voltage than  $V_{th}$  and  $V_{GS}$  (off) requires a lower voltage than  $V_{th}$ . (The relationship can be established as follows:  $V_{GS}$  (off) <  $V_{th}$  <  $V_{GS}$  (on).)

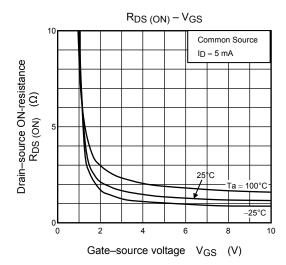
Take this into consideration when using the device.

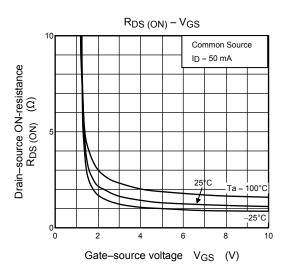
#### **Handling Precaution**

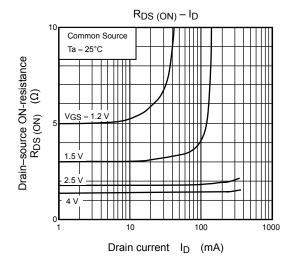
When handling individual devices that are not yet mounted on a circuit board, make sure that the environment is protected against electrostatic discharge. Operators should wear antistatic clothing, and containers and other objects that come into direct contact with devices should be made of antistatic materials.

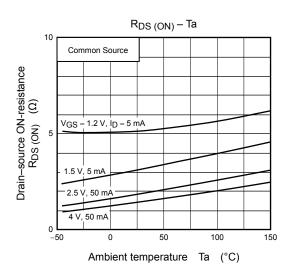


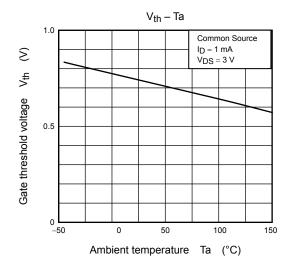


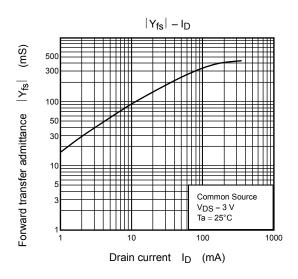


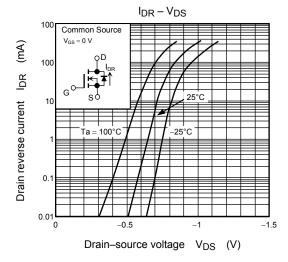


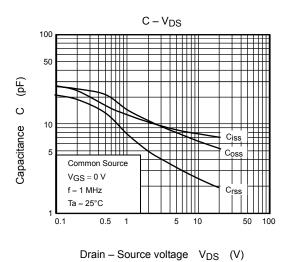


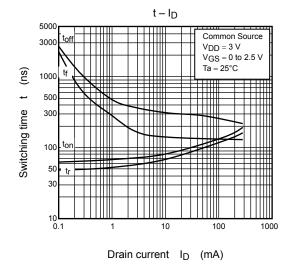


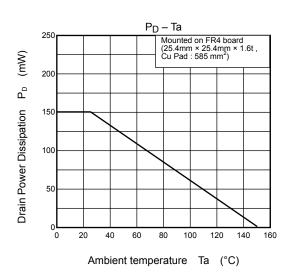












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